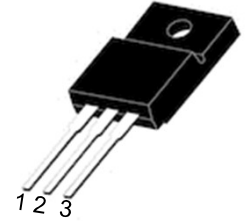
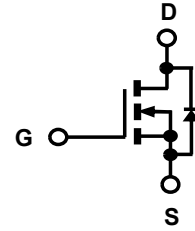


ICEK9NF65FP N-Channel Enhancement Mode MOSFET

Features

- Low $r_{DS(on)}$
- Ultra Low Gate Charge
- High dv/dt capability
- High Unclamped Inductive Switching (UIS) capability
- High peak current capability
- Increased transconductance performance
- Optimized design for high performance power systems

| Product Summary | | | |
|-----------------|------------------------|-------|-----|
| I_D | $T_A=25^\circ\text{C}$ | 9.1A | Max |
| $V_{(BR)DSS}$ | $I_D=250\mu\text{A}$ | 650V | Min |
| $r_{DS(on)}$ | $V_{GS}=10\text{V}$ | 0.302 | Typ |
| Q_g | $V_{DS}=480\text{V}$ | 20nC | Typ |



T0220FP

Isolated (T0-220)

1=Gate, 2=Drain,
3=Source.



Lead Free

Maximum ratings^a, at $T_j=25^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Value | Unit |
|--|----------------|---|-------------|------------------|
| Continuous drain current ^b | I_D | $T_c=25^\circ\text{C}$ | 9.1 | A |
| | | $T_c=100^\circ\text{C}$ | 5.7 | |
| Pulsed drain current ^b | $I_{D, pulse}$ | $T_c=25^\circ\text{C}$ | 34 | A |
| Avalanche energy, single pulse | E_{AS} | $L = 75 \text{ mH}, V_{DD} = 100 \text{ V}, I_D=1.2\text{A}, R_G = 50 \Omega$ | 54 | mJ |
| Avalanche current, repetitive ^b | I_{AR} | limited by T_{jmax} | 1.2 | A |
| MOSFET dv/dt ruggedness | dv/dt | $V_{DS}=480\text{V}$ | 50 | V/ns |
| Reverse diode dv/dt ruggedness | | | 50 | |
| Gate source voltage | V_{GS} | Static | ± 30 | V |
| | | AC ($f>1\text{Hz}$) | | |
| Power dissipation | P_{tot} | $T_c=25^\circ\text{C}$ | 43.1 | W |
| Operating and storage temperature | T_j, T_{stg} | | -55 to +150 | $^\circ\text{C}$ |

a Preliminary data sheet - Specifications subject to change.

b limited by T_{jmax}

c when mounted on 1-inch square 2oz copper-clad FR-4

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|-----|-----|------|
| | | | Min | Typ | Max | |

Thermal characteristics

| | | | | | | |
|---|------------|-------------------------------------|---|---|-----|------|
| Thermal resistance, junction-case | R_{thJC} | | - | - | 2.9 | °C/W |
| Thermal resistance, junction-ambient ° | R_{thJA} | leaded | - | - | 55 | |
| Soldering temperature, wave soldering only allowed at leads | T_{sold} | 1.6mm (0.063in.) from case for 10 s | - | - | 260 | °C |

Electrical characteristics, at $T_j=25^{\circ}\text{C}$, unless otherwise specified

Static characteristics

| | | | | | | |
|----------------------------------|---------------|--|-----|-------|-----------|---------------|
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | $V_{GS}=0\text{ V}, I_D=250\mu\text{A}$ | 650 | - | - | V |
| Gate threshold voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}, I_D=250\mu\text{A}$ | 2.5 | 3.4 | 4.5 | |
| Zero gate voltage drain current | I_{DSS} | $V_{DS}=650\text{V}, V_{GS}=0\text{V}$ | - | - | 10 | μA |
| Gate source leakage current | I_{GSS} | $V_{GS}=\pm 30\text{ V}, V_{DS}=0\text{V}$ | - | - | ± 100 | nA |
| Drain-source on-state resistance | $R_{DS(on)}$ | $V_{GS}=10\text{V}, I_D=5\text{A}$ | - | 0.302 | 0.36 | Ω |
| Gate resistance | R_G | $f=1\text{ MHz}, \text{open drain}$ | - | 16 | - | Ω |

Dynamic characteristics

| | | | | | | |
|------------------------------|--------------|--|---|-----|---|----|
| Input capacitance | C_{iss} | $V_{DS}=400\text{ V}, V_{GS}=0\text{ V}, f=1\text{ MHz}$ | - | 530 | - | pF |
| Output capacitance | C_{oss} | | - | 15 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 5.5 | - | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DS}=400\text{V}, V_{GS}=10\text{V}, I_D=5\text{A}, R_G=5\Omega \text{ (External)}$ | - | 52 | - | ns |
| Rise time | t_r | | - | 7 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 37 | - | |
| Fall time | t_f | | - | 10 | - | |

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|-----|-----|------|
| | | | Min | Typ | Max | |

Gate charge characteristics

| | | | | | | |
|-----------------------|----------|--|---|----|---|----|
| Gate to source charge | Q_{gs} | $V_{DS}=480\text{ V}, I_D=9.1\text{ A},$ $V_{GS}=0\text{ to }10\text{ V}$ | - | 4 | - | nC |
| Gate to drain charge | Q_{gd} | | - | 11 | - | |
| Gate charge total | Q_g | | - | 20 | - | |

Reverse Diode

| | | | | | | |
|-------------------------------|----------|---|---|------|-----|---------------|
| Continuous forward current | I_S | $V_{GS}=0\text{ V}$ | - | - | 9.1 | A |
| Diode forward voltage | V_{SD} | $V_{GS}=0\text{ V}, I_S=5\text{ A}$ | - | 1.05 | - | V |
| Reverse recovery time | t_{rr} | $V_{RR}=400\text{ V}, I_S=5\text{ A},$ $d_{iF}/d_t=100\text{ A}/\mu\text{S}$ | - | 59 | - | ns |
| Reverse recovery charge | Q_{rr} | | - | 0.35 | - | μC |
| Peak reverse recovery current | I_{rm} | | - | 13 | - | A |

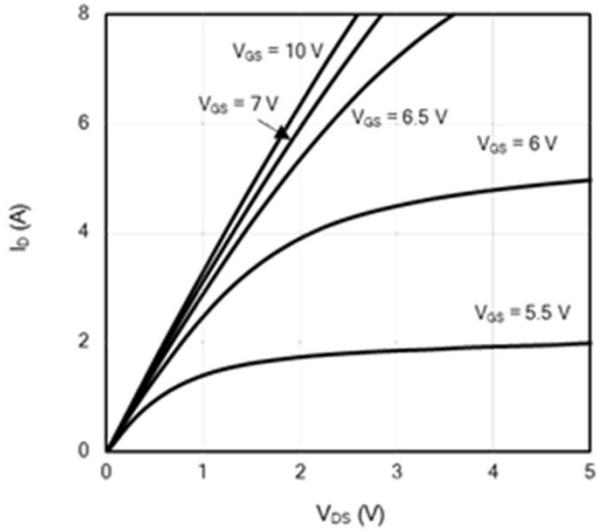


Figure 1: On-Region Characteristics

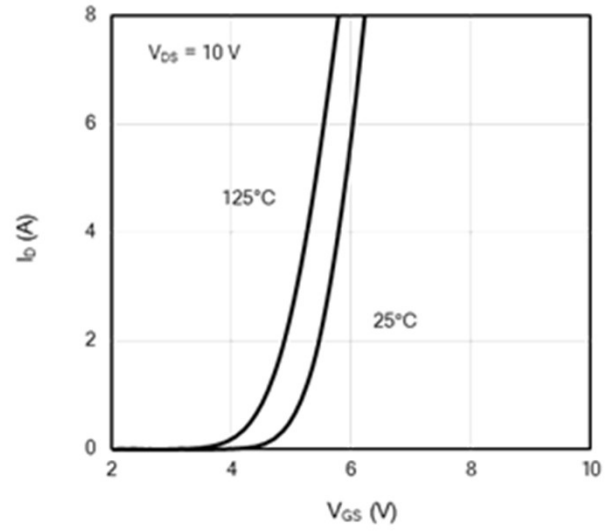


Figure 2: Transfer Characteristics

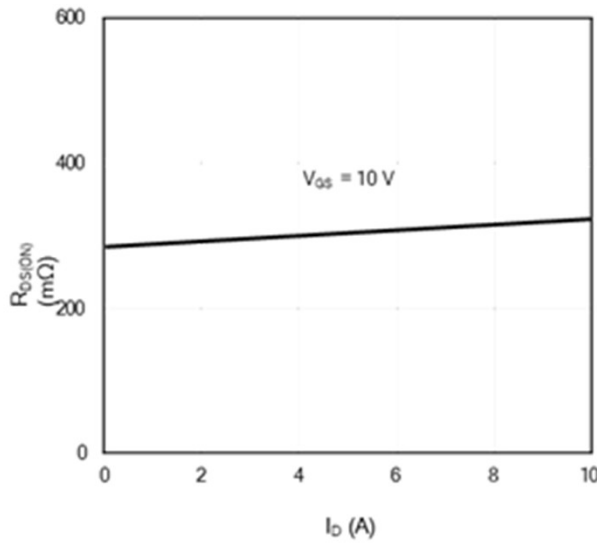


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

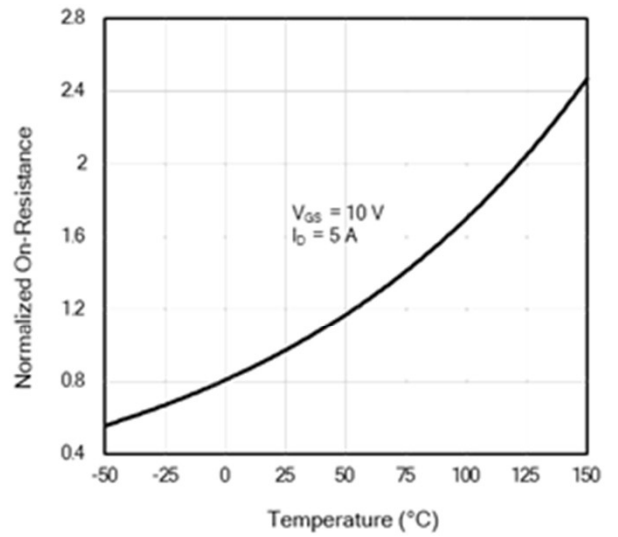


Figure 4: On-Resistance vs. Junction Temperature

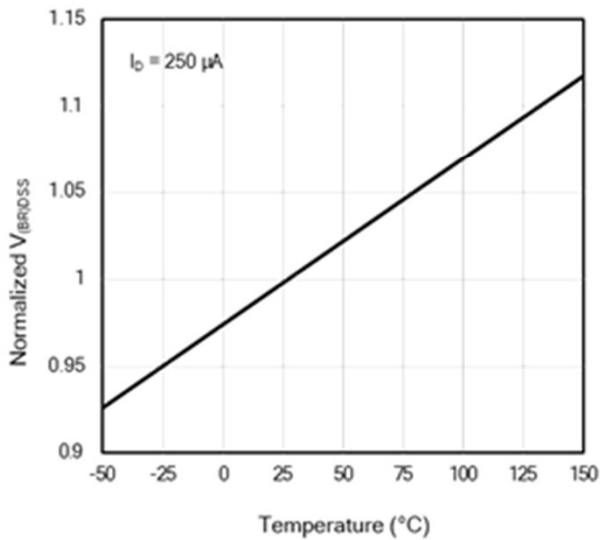


Figure 5: Breakdown Voltage vs. Junction Temperature

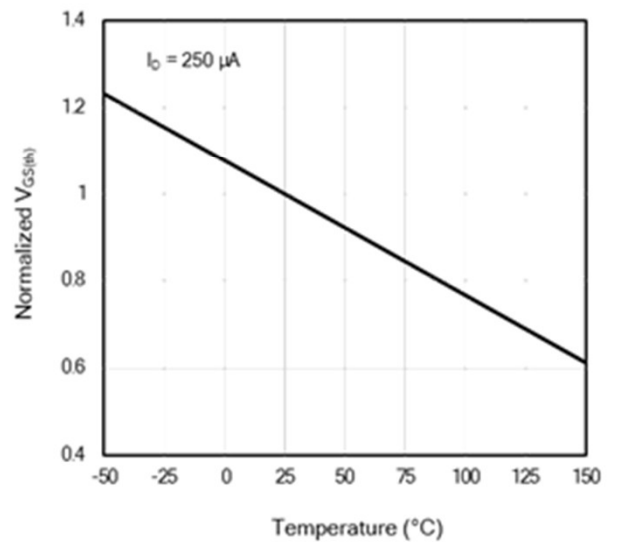


Figure 6: Threshold Voltage vs. Junction Temperature

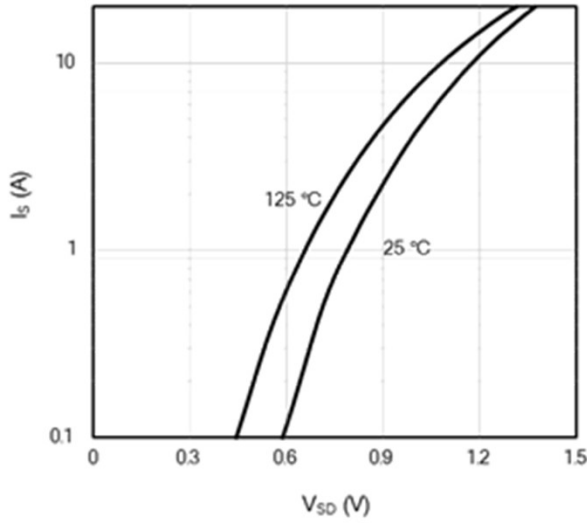


Figure 7: Body-Diode Characteristics

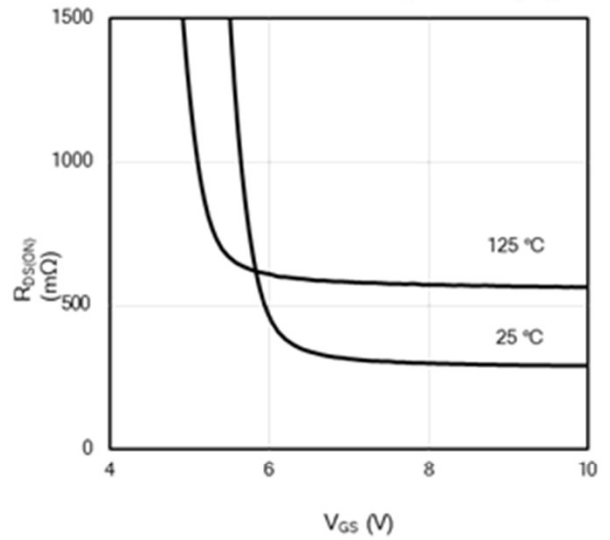


Figure 8: On-Resistance vs. Gate-Source Voltage

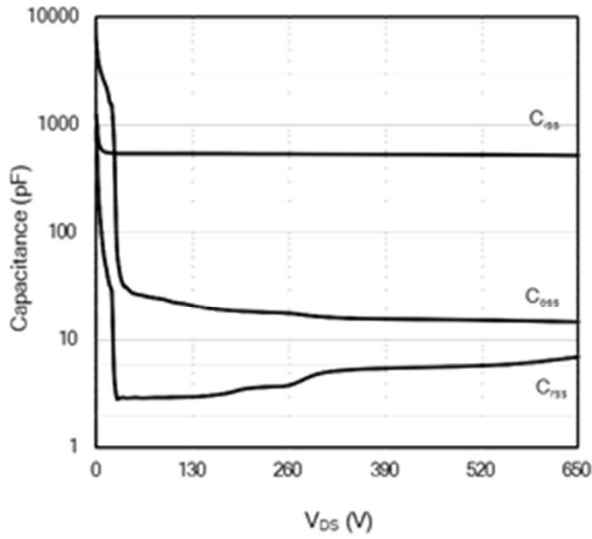


Figure 9: Capacitance Characteristics

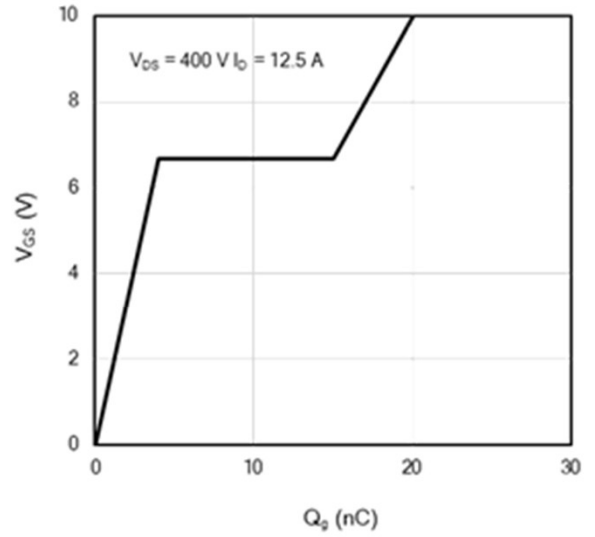


Figure 10: Gate-Charge Characteristics

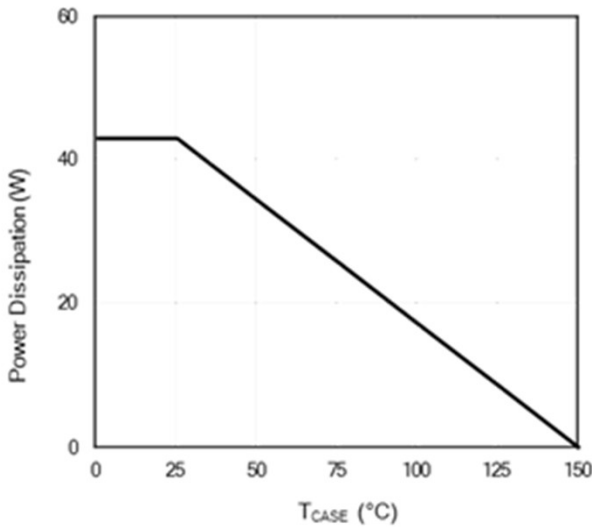


Figure 11: Power De-rating

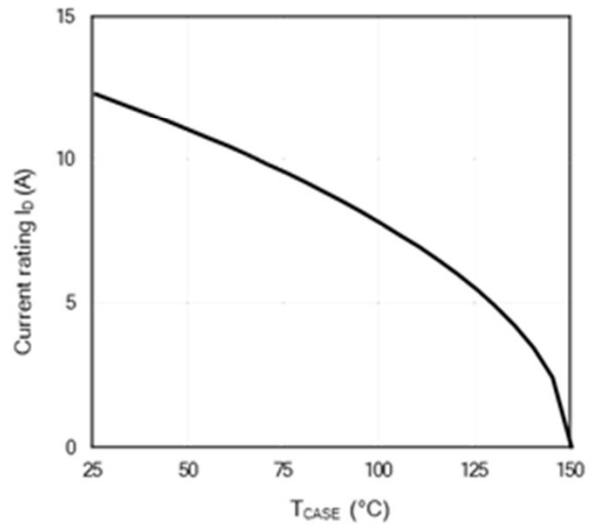


Figure 12: Current De-rating

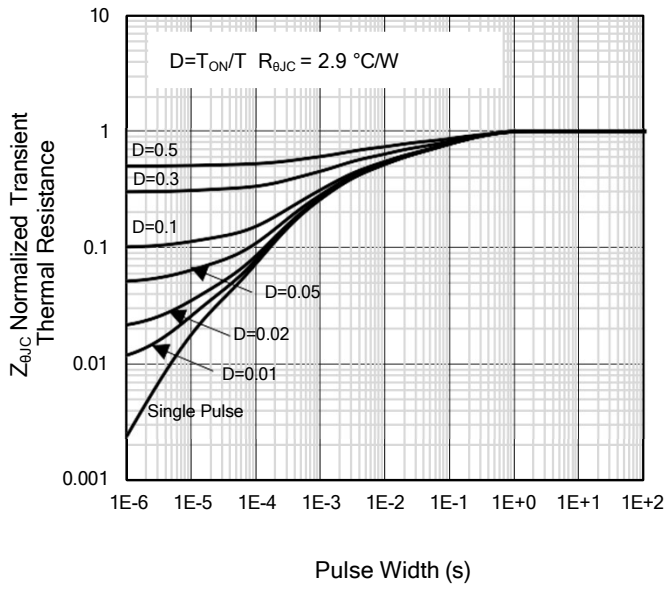


Figure 13: Normalized Maximum Transient Thermal Impedance

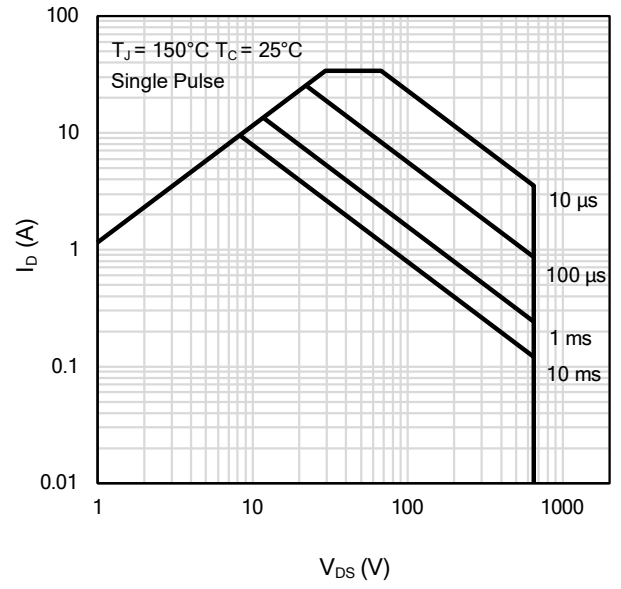


Figure 14: Maximum Forward Biased Safe Operating Area

Marking Information

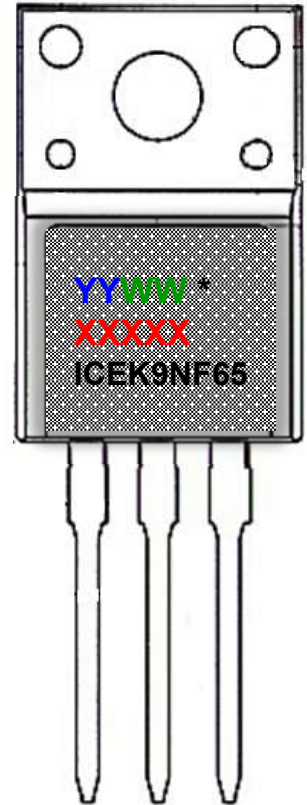
YY = Last two digits of the year

WW = Work week

***** = Site ID

XXXXX = Lot ID

ICEK9NF65 = ICE is IceMOS logo and
K9NF65 is a designated device part
number



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